

# 40468A, 40559A

## MOS Silicon Transistors N-Channel Depletion Types

### For RF Amplifier and Mixer Applications in FM and AM/FM Receivers

RCA-40468A and 40559A are silicon insulated-gate field-effect transistors of the n-channel depletion type utilizing the MOS\* construction. They are intended primarily for use as the rf amplifier and mixer, respectively, in FM receivers covering the 88 to 108 MHz band, but can be used for general amplifier applications at frequencies up to 125 MHz. For circuit design and typical performance data refer to RCA Application Note AN3535 "An FM Tuner Using Single-Gate MOS Field-Effect Transistors as RF Amplifier and Mixer".

The wide dynamic range of these transistors reduces cross-modulation effects in AM receivers and minimizes the generation of spurious responses in FM receivers.

Operating as a neutralized amplifier at 100 MHz, the 1A can provide a power gain of 17 dB (typ.). A gain of 14 dB (typ.) can be realized without neutralization.

\* Metal-Oxide-Semiconductor.

#### Performance Features:

- reduced spurious responses in FM tuners
- reverse bias on substrate improves linearity
- reduced cross-modulation effects in AM receivers

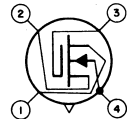
#### Maximum Ratings, Absolute-Maximum Values at $T_A = 25^\circ\text{C}$ :

DRAIN-TO-SOURCE VOLTAGE, $V_{DS}$	.....	+20	V
DRAIN-TO-GATE VOLTAGE, $V_{DG}$	.....	+20	V
GATE-TO-SOURCE VOLTAGE, $V_{GS}$ :			
CONTINUOUS (dc)	.....	+1, -8	V
PEAK ac	.....	$\pm 15$	V
DRAIN CURRENT, $I_D$	.....	25	mA
TRANSISTOR DISSIPATION:			
At ambient	.....	330	mW
temperatures	.....	up to $25^\circ\text{C}$	
above $25^\circ\text{C}$	.....	derate at 2.2 mW/ $^\circ\text{C}$	
AMBIENT TEMPERATURE RANGE:			
Storage	.....	-65 to +175	$^\circ\text{C}$
Operating	.....	-65 to +175	$^\circ\text{C}$
LEAD TEMPERATURE (During Soldering):			
At distances not closer than 1/32 inch to seating surface for 10 seconds maximum	.....	265	$^\circ\text{C}$

#### Device Features:

- high forward transconductance --  
gfs = 7500  $\mu\text{mho}$  typ. for 40468A
- low feedback capacitance --  
 $C_{rss} = 0.35$  pF max. for 40468A  
0.38 pF max. for 40559A
- high useful power gains --  
neutralized - 17 dB typ.  
unneutralized - 14 dB typ.
- hermetically sealed in TO-72 metal package

#### TERMINAL DIAGRAM



LEAD 1 - DRAIN  
LEAD 2 - SOURCE  
LEAD 3 - INSULATED GATE  
LEAD 4 - BULK (SUBSTRATE) AND CASE

### ELECTRICAL CHARACTERISTICS, at $T_A = 25^\circ\text{C}$ With Bulk (Substrate) Connected to Source Unless Otherwise Specified

Characteristics	Symbols	TEST CONDITIONS			LIMITS						Units
		Frequency	DC Drain-to-Source VDS	DC Drain Current ID	RCA-40468A RF Amplifier			RCA-40559A Mixer			
		f MHz	V	mA	Min.	Typ.	Max.	Min.	Typ.	Max.	
Drain-to-Source Cutoff Current	ID(off)	-	12	VGS = -8V	-	-	100	-	-	500	μA
Gate Leakage Current	IGSS	-	0	VGS = -8V VGS = +1V	-	-	1	-	-	1	nA
Zero-Bias Drain Current	IDSS	-	15	VGS = 0	5	15	30	5	15	30	mA
Small-Signal, Short-Circuit Forward Transconductance	gfs	1 kHz	15	5	-	7500	-	-	-	-	μmho
Small-Signal, Short-Circuit Reverse-Transfer Capacitance (Drain-to-Gate)	Crss	1	15	5	-	0.25	0.35	-	0.25	0.38	pF
Input Capacitance	Ciss	1	15	5	-	5.5	-	-	5.5	-	pF
Admittance	-	RF Mixer		RF Mixer	-			-			-
Input Admittance	Yis	100 MHz	15	5	3	0.155 + j 3.45		0.14 + j 3.38			mmho
Forward Transfer Admittance	Yfs	100 MHz	15	5	3	7.4 + j 0.9		-			mmho
Output Admittance	Yos	100 MHz 10.7 MHz	15	5	3	0.21 + j 0.9		0.076 + j 0.153			mmho
Forward Conversion Transconductance	gfs(c)	1 kHz	15	3	-	-	-	-	2800*	-	μmho
Maximum Available Power Gain	MAG	100	15	5	-	26	-	-	-	-	dB
Maximum Usable Power Gain (Unneutralized)	MUG	100	15	5	-	14	-	-	-	-	dB
Maximum Usable Power Gain (Neutralized)	MUG	100	15	5	14	17	-	-	-	-	dB
Maximum Available Conversion Gain	MAGc	f <sub>in</sub> = 100 MHz f <sub>out</sub> = 10.7	15	3	-	-	-	-	22	-	dB
Noise Figure	NF	100	15	5	-	3.5	5	-	-	-	dB

\* Bulk (Substrate)-to-Source Volts (V<sub>BS</sub>) = -3.

For characteristics curves, refer to types 3N128 and 3N143.

# 40600, 40601, 40602

## SILICON DUAL INSULATED-GATE FIELD-EFFECT TRANSISTORS

### N-Channel Depletion Types

### For VHF TV Receiver Applications

RCA 40600, 40601, and 40602 are n-channel depletion type, dual-insulated-gate, field-effect transistors utilizing the MOS construction. These devices have characteristics which make them highly desirable for rf-amplifier applications (40600), mixer applications (40601), and first-if-amplifier applications (40602) in vhf TV receivers and other types of commercial equipment operating at frequencies up to approximately 250 MHz.

These transistors feature a series arrangement of two separate channels, each channel having an independent control gate. In amplifier applications the 40600 and 40602 with their wide dynamic range provide substantially better cross-modulation performance than is obtainable with bipolar or single-gate field-effect transistors. In mixer applications the 40601 provides excellent isolation between the oscillator and rf signals because each of the two signal frequencies being mixed has its own control element. The wide dynamic range of the 40601 minimizes cross-modulation which is generally encountered in mixer stages.

Provision of two insulated gates also results in extremely low feedback capacitances (0.02 pF typ.), a feature which enables the 40600 and 40602 to provide high maximum useable power gains in unneutralized circuits — for example, 20 dB at 200 MHz typ\* for the

40600, and 35 dB typ. at 44 MHz for the 40602. The gain of the rf and if stages can be controlled by applying agc voltage to gate No.2 and agc delay is easily obtained. Virtually no agc power is required for full gain reduction.

Types 40600, 40601, and 40602 are hermetically sealed in metal JEDEC TO-72 packages.

### APPLICATIONS

- VHF TV Receiver
  - 40600 for rf amplifier applications
  - 40601 for mixer applications
  - 40602 for first-if-amplifier applications

### PERFORMANCE FEATURES

- superior cross-modulation performance and greater dynamic range than bipolar and single-gate field-effect transistors
- permits use of vacuum-tube biasing techniques
- excellent thermal stability

### ELECTRICAL CHARACTERISTICS, at $T_A = 25^\circ\text{C}$

CHARACTERISTICS	SYMBOLS	TEST CONDITIONS	LIMITS			UNITS
			40600, 40601, 40602			
			Min.	Typ.	Max.	
Gate No.1-to-Source Cutoff Voltage	$V_{G1S(off)}$	$V_{DS} = +15V, I_D = 200 \mu A$ $V_{G2S} = +4V$	-	-2	-	V
Gate No.2-to-Source Cutoff Voltage	$V_{G2S(off)}$	$V_{DS} = +15V, I_D = 200 \mu A$ $V_{G1S} = 0$	-	-2	-	V
Gate No.1 Leakage Current	$I_{G1SS}$	$V_{G1S} = -20V, V_{G2S} = 0, V_{DS} = 0$	-	-	1	nA
Gate No.2 Leakage Current	$I_{G2SS}$	$V_{G2S} = -20V, V_{G1S} = 0, V_{DS} = 0$	-	-	1	nA
Drain Current	$I_{DSS}$	$V_{DS} = +13V, V_{G1S} = 0, V_{G2S} = +4V$	-	18	-	mA
Forward Transconductance	$g_{fs}$	$V_{DS} = +13V, I_D = 10 \text{ mA}$ $V_{G2S} = +4V, f = 1 \text{ kHz}$	-	10000	-	$\mu\text{mho}$

### TYPICAL PERFORMANCE CHARACTERISTICS, at $T_A = 25^\circ\text{C}$

CHARACTERISTICS	SYMBOLS	40600 RF AMPLIFIER f = 200 MHz	40602 IF AMPLIFIER f = 44 MHz	40601 MIXER f = 200 MHz	UNITS
		VG1S is adjusted for ID = 10 mA Gate No.2 at AC ground potential VDS = 13V, VG2S = +4V			
Small-Signal, Short Circuit Reverse-Transfer Capacitance (Drain-to-Gate No.1) at f = 1 MHz	Crss	0.02 typ. 0.03 max.	0.02 typ. 0.03 max.	0.02 typ. 0.03 max.	pF
Output Capacitance	Coss	2.2	2.2	2.2 at f = 44 MHz	pF
Input Capacitance	Ciss	5.5	5.5	5.5	pF
Input Resistance	riss	1.2	10	1.2	KΩ
Output Resistance	ross	2.8	12	12 at f = 44 MHz	KΩ
Magnitude of Forward Transadmittance	Yfs	11000	11000	2700*	μmho
Phase Angle of Forward Transadmittance	∠θ	-46	-11	-	degrees
Maximum Available Power Gain	MAG	20	35	14**	dB
Maximum Usable Power Gain (Unneutralized)	MUGu	20^A	1 Stage 28 2 Stages 26 3 Stages 24	- - -	dB dB dB
Power Gain See Fig.1 for measurement circuit	Gps	17.5	-	-	dB
Noise Figure	NF	5 max.	-	-	dB

\* Magnitude of forward conversion transmittance

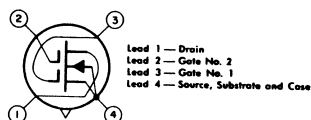
\*\* Maximum available conversion gain

Δ Limited by practical design considerations

### DEVICE FEATURES

- extremely low feedback capacitance  
 $C_{rss} = 0.02 \text{ pF typ.}$
- high power gain  
 $MUG_u = 20 \text{ dB typ. for 40600}$   
 $MAG = 35 \text{ dB typ. for 40602}$   
 $MAG_c = 14 \text{ dB typ. for 40601}$

### TERMINAL DIAGRAM



### Maximum Ratings, Absolute-Maximum Values at $T_A = 25^\circ\text{C}$ :

DRAIN-TO-SOURCE VOLTAGE, $V_{DS}$	0 to +20	V
GATE No.1-TO-SOURCE VOLTAGE, $V_{G1S}$		
Continuous (dc)	+1 to -8	V
Peak ac	+20 to -8	V
GATE No.2-TO-SOURCE VOLTAGE, $V_{G2S}$		
Continuous (dc)	-8 to 40% of $V_{DS}$	V
Peak ac	-8 to +20	V
DRAIN-TO-GATE VOLTAGE, $V_{DG1}$ or $V_{DG2}$	+20	V
DRAIN CURRENT, $I_D$ (Pulsed):		
Pulse duration $\leq 20 \text{ ms}$ , duty factor $\leq 0.15$	50	mA

### TRANSISTOR DISSIPATION, $P_T$ :

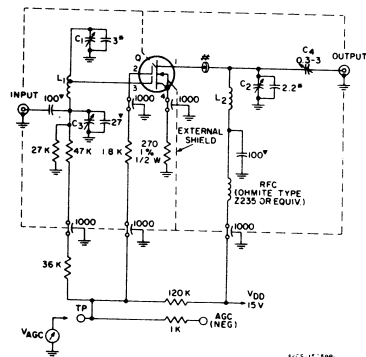
At ambient $\left\{ \begin{array}{l} \text{up to } 25^\circ\text{C} \\ \text{above } 25^\circ\text{C} \end{array} \right.$	400	mW
temperatures $\left\{ \begin{array}{l} \text{up to } 25^\circ\text{C} \\ \text{above } 25^\circ\text{C} \end{array} \right.$	derate linearly at	$2.67 \text{ mW}/^\circ\text{C}$

### AMBIENT TEMPERATURE RANGE:

Storage and Operating  $-65$  to  $+175^\circ\text{C}$

### LEAD TEMPERATURE (During soldering):

At distances  $\geq 1/32"$  from seating surface for 10 seconds max.  $265^\circ\text{C}$



\* Tubular ceramic.

Δ Disk ceramic.

# Ferrite bead ( $1/2$  used); Indiana General No. H1742C-(A-147) or F1157-1-H, or equivalent.

$C_1, C_2$ : 1.5-5 pF variable air capacitor: E. F. Johnson Type 160-10\*, or equivalent.

$C_3$ : 1-10 pF piston-type variable air capacitor: JFD Type VAM-010, Johnson Type 4335, or equivalent.

$C_4$ : 0.3-3 pF piston-type variable air capacitor: Roanwell Type MH-13, or equivalent.

$L_1$ : 5 turns silver-plated 0.02" thick, 0.07"-0.08" wide copper ribbon. Internal diameter of winding  $\approx 0.25"$ ; winding length approx. 0.65". Tapped at 1-1/2 turns from  $C_1$  end of winding.

$L_2$ : Same as  $L_1$  except winding length approx. 0.7", no tap.

Fig.1 - 200 MHz Power Gain and Noise Figure Test Circuit for 40600 and 40602

For characteristics curves, refer to type 3N140.

# SILICON DUAL INSULATED-GATE FIELD-EFFECT TRANSISTORS

## N-Channel Depletion Types For FM Tuner Applications

RCA 40603 and 40604 are n-channel silicon, depletion type, dual insulated-gate, field-effect transistors utilizing the MOS construction.

These devices have exceptional characteristics for rf-amplifier (40603) and mixer applications (40604) in FM tuners and other commercial equipment operating at frequencies up to approximately 150 MHz. These transistors feature a series arrangement of two separate channels, each channel having an independent control gate. For amplifier applications the 40603 with its wide dynamic range provides substantially better cross-modulation performance and relative freedom from spurious responses than is obtainable with bipolar or single-gate field-effect transistors. The mixing function performed by the 40604 is unique in that the signal applied to gate No.2 is used to modulate the input-gate (gate No.1) vfer characteristic. This technique is superior to ventional "square law" mixing, which can only be accomplished in the non-linear region of the device transfer characteristic.

Because of the low feedback capacitance (0.02 typ. pF) the 40603 can provide a power gain of 25 dB (typ.) at 100 MHz in an unneutralized amplifier circuit.

The gain of the rf stage can be controlled by applying agc voltage to gate No.2. Virtually no agc power is required for full gain reduction.

The 40603 and 40604 are hermetically sealed in JEDEC TO-72 packages.

### Maximum Ratings, Absolute-Maximum Values at $T_A = 25^\circ\text{C}$ :

DRAIN-TO-SOURCE VOLTAGE, $V_{DS}$	0 to +20	V
GATE No.1-TO-SOURCE VOLTAGE, $V_{G1S}$ :		
Continuous (dc)	-8 to +1	V
Peak ac	-8 to +20	V
GATE No.2-TO-SOURCE VOLTAGE, $V_{G2S}$ :		
Continuous (dc)	-8 to 40% of $V_{DS}$	V
Peak ac	-8 to +20	V
DRAIN-TO-GATE VOLTAGE, $V_{DG1}$ or $V_{DG2}$	+20	V
DRAIN CURRENT, $I_D$ (Pulsed):		
Pulse duration $\leq 20$ ms, duty factor $\leq 0.15$	50	mA
TRANSISTOR DISSIPATION, $P_T$ :		
At ambient temperatures up to $25^\circ\text{C}$	400	mW
temperatures above $25^\circ\text{C}$	derate linearly at 2.67 mW/ $^\circ\text{C}$	
AMBIENT TEMPERATURE RANGE:		
Storage and Operating	-65 to +175	$^\circ\text{C}$
LEAD TEMPERATURE (During soldering):		
At distances $> 1/32"$ from seating surface for 10 seconds max.	265	$^\circ\text{C}$

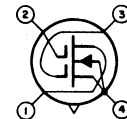
### PERFORMANCE FEATURES

- large dynamic range permits large-signal handling before overload
- dual gates allow product mixing with extremely low harmonic generation
- greatly reduces spurious responses in FM receivers
- permits use of vacuum-tube biasing techniques
- excellent thermal stability
- superior cross-modulation performance and greater dynamic range than bipolar and single-gate field-effect transistors

### DEVICE FEATURES

- extremely low feedback capacitance  $C_{rss} = 0.02$  pF typ.
- high unneutralized RF power gain  $MUG = 25$  dB (typ.) for 40603
- low noise figure  $NF = 2.5$  dB typ. for 40603

### TERMINAL DIAGRAM



Lead 1 — Drain  
Lead 2 — Gate No. 2  
Lead 3 — Gate No. 1  
Lead 4 — Source, Substrate and Case

### ELECTRICAL CHARACTERISTICS, at $T_A = 25^\circ\text{C}$

CHARACTERISTICS	SYMBOLS	TEST CONDITIONS	LIMITS				UNITS
			40603 RF AMPLIFIER		40604 MIXER		
			Typ.	Max.	Typ.	Max.	
Gate No.1-to-Source Cutoff Voltage	V <sub>G1S(off)</sub>	V <sub>DS</sub> = +15 V, I <sub>D</sub> = 200 μA V <sub>G2S</sub> = +4 V	-2	--	-2	--	V
Gate No.2-to-Source Cutoff Voltage	V <sub>G2S(off)</sub>	V <sub>DS</sub> = +15 V, I <sub>D</sub> = 200 μA V <sub>G1S</sub> = 0	-2	--	-2	--	V
Gate No.1 Leakage Current	I <sub>G1SS</sub>	V <sub>G1S</sub> = -20 V, V <sub>G2S</sub> = 0, V <sub>DS</sub> = 0	--	1	--	1	nA
Gate No.2 Leakage Current	I <sub>G2SS</sub>	V <sub>G2S</sub> = -20 V, V <sub>G1S</sub> = 0, V <sub>DS</sub> = 0	--	1	--	1	nA
Zero-Bias-Voltage Drain Current	I <sub>DSS</sub>	V <sub>G2S</sub> = +4 V, V <sub>G1S</sub> = 0, V <sub>DS</sub> = +13 V	18	--	18	--	mA
Small-Signal, Short-Circuit Reverse-Transfer Capacitance (Drain-to-Gate-No.1)	C <sub>rss</sub>	V <sub>DS</sub> = +13 V, I <sub>D</sub> = 10 mA, f = 1 MHz V <sub>G2S</sub> = +4 V	0.02	0.03	0.02	0.03	pF
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> = +13 V, I <sub>D</sub> = 10 mA V <sub>G2S</sub> = +4 V, f = 1 MHz	5.5	--	5.5	--	pF
Output Capacitance	C <sub>oss</sub>	V <sub>DS</sub> = +13 V, I <sub>D</sub> = 10 mA V <sub>G2S</sub> = +4 V, f = 100 MHz	2.1	--	2.3	--	pF
Input Resistance	r <sub>is</sub>	V <sub>DS</sub> = +13 V, I <sub>D</sub> = 10 mA V <sub>G2S</sub> = +4 V, f = 100 MHz	3.5	--	3.5	--	kΩ
Output Resistance	r <sub>os</sub>	V <sub>DS</sub> = +13 V I <sub>D</sub> = 10 mA V <sub>G2S</sub> = +4 V f = 10.7 MHz	4 --	-- --	-- 20	-- --	kΩ
Forward Transconductance	g <sub>fs</sub>	V <sub>DS</sub> = +13 V, I <sub>D</sub> = 10 mA V <sub>G2S</sub> = +4 V, f = 1 kHz	10,000	--	2800*	--	μmho
Maximum Available Power Gain	MAG	V <sub>DS</sub> = +13 V, I <sub>D</sub> = 10 mA V <sub>G2S</sub> = +4 V	26	--	21	--	dB
Maximum Usable Power Gain (Unneutralized)	MUG	V <sub>DS</sub> = +13 V, I <sub>D</sub> = 10 mA V <sub>G2S</sub> = +4 V f = 100 MHz, f <sub>out</sub> for 40604 (mixer) = 10.7 MHz	25 <sup>A</sup>	--	--	--	dB
Noise Figure	NF		2.5	--	--	--	dB

\* conversion transconductance

<sup>A</sup> or limited by design considerations

For characteristics curves, refer to type 3N140.

SILICON DUAL INSULATED-GATE FIELD-EFFECT TRANSISTOR  
N-Channel Depletion Type With Integrated  
Gate-Protection Circuits  
For RF Amplifier Applications up to 400 MHz

RCA-40673 is an n-channel silicon, depletion type, dual insulated-gate field-effect transistor.

Special back-to-back diodes are diffused directly into the MOS<sup>®</sup> pellet and are electrically connected between each insulated gate and the FET's source. The diodes effectively bypass any voltage transients which exceed approximately ±10 volts. This protects the gates against damage in all normal handling and usage.

A feature of the back-to-back diode configuration is that it allows the 40673 to retain the wide input signal dynamic range inherent in the MOSFET. In addition, the low junction capacitance of these diodes adds little to the total capacitance shunting the signal gate.

The excellent overall performance characteristics of the RCA-40673 make it useful for a wide variety of rf-amplifier applications at frequencies up to 400 MHz. The two serially-connected channels with independent control gates make possible a greater dynamic range and lower cross-modulation than is normally achieved using devices having only a single control element.

The two gate arrangement of the 40673 also makes possible a desirable reduction in feedback capacitance by operating in

the common-source configuration and ac-grounding Gate No. 2. The reduced capacitance allows operation at maximum gain *without neutralization*; and, of special importance in rf-amplifiers, it reduces local oscillator feedthrough to the antenna.

The 40673 is hermetically sealed in the metal JEDEC TO-72 package.

\*Metal-Oxide-Semiconductor.

Maximum Ratings, Absolute-Maximum Values, at T <sub>A</sub> = 25°C	
DRAIN-TO-SOURCE VOLTAGE, V <sub>DS</sub> .....	-0.2 to +20 V
GATE No.1-TO-SOURCE VOLTAGE, V <sub>G1S</sub> :	
Continuous (dc).....	-6 to +1 V
Peak ac.....	-6 to +6 V
GATE No.2-TO-SOURCE VOLTAGE, V <sub>G2S</sub> :	
Continuous (dc).....	-6 to +6 V
Peak ac.....	-6 to +6 V
DRAIN-TO-GATE VOLTAGE, V <sub>DG1</sub> OR V <sub>DG2</sub> .....	+20 V
DRAIN CURRENT, I <sub>D</sub> .....	50 mA
TRANSISTOR DISSIPATION, P <sub>T</sub> :	
At ambient temperatures up to 25°C.....	330 mW
At distances ≥ 1/32 inch from seating surface for 10 seconds max. above 25°C.....	derate linearly at 2.2 mW/°C
AMBIENT TEMPERATURE RANGE:	
Storage and Operating.....	-65 to +175 °C
LEAD TEMPERATURE (During soldering):	
At distances ≥ 1/32 inch from seating surface for 10 seconds max. ....	265 °C

ELECTRICAL CHARACTERISTICS, at T<sub>A</sub> = 25°C unless otherwise specified

CHARACTERISTICS	SYMBOLS	TEST CONDITIONS	LIMITS			UNITS
			Min.	Typ.	Max.	
Gate-No.1-to-Source Cutoff Voltage	V <sub>G1S(off)</sub>	V <sub>DS</sub> = +15V, I <sub>D</sub> = 200 μA V <sub>G2S</sub> = +4V	-	-2	-4	V
Gate-No.2-to-Source Cutoff Voltage	V <sub>G2S(off)</sub>	V <sub>DS</sub> = +15V, I <sub>D</sub> = 200 μA V <sub>G1S</sub> = 0	-	-2	-4	V
Gate-No.1-Leakage Current	I <sub>G1SS</sub>	V <sub>G1S</sub> = +1 or -6 V V <sub>DS</sub> = 0, V <sub>G2S</sub> = 0	-	-	50	nA
Gate-No.2-Leakage Current	I <sub>G2SS</sub>	V <sub>G2S</sub> = +6V V <sub>DS</sub> = 0, V <sub>G1S</sub> = 0	-	-	50	nA
Zero-Bias Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = +15V V <sub>G2S</sub> = +4V V <sub>G1S</sub> = 0	5	15	35	mA
Forward Transconductance (Gate-No.1-to-Drain)	g <sub>fs</sub>	V <sub>DS</sub> = +15V, I <sub>D</sub> = 10mA V <sub>G2S</sub> = +4V, f = 1kHz	-	12,000	-	μmho
Small-Signal, Short-Circuit Input Capacitance †	C <sub>iss</sub>	V <sub>DS</sub> = +15V, I <sub>D</sub> = 10mA V <sub>G2S</sub> = +4V, f = 1MHz	-	6	-	pF
Small-Signal, Short-Circuit, Reverse Transfer Capacitance (Drain-to-Gate No.1) ‡	C <sub>rss</sub>		0.005	0.02	0.03	pF
Small-Signal, Short-Circuit Output Capacitance	C <sub>oss</sub>		-	2.0	-	pF
Power Gain (see Fig. 1)	G <sub>PS</sub>	V <sub>DS</sub> = +15V, I <sub>D</sub> = 10mA V <sub>G2S</sub> = +4V, f = 200 MHz	14	18	-	dB
Maximum Available Power Gain	MAG		-	20	-	dB
Maximum Usable Power Gain (unneutralized)	MUG		-	20*	-	dB
Noise Figure (see Fig. 1)	NF		-	3.5	6.0	dB
Magnitude of Forward Transadmittance	Y <sub>fs</sub>		-	12,000	-	μmho
Phase Angle of Forward Transadmittance	θ		-	-35	-	degrees
Input Resistance	r <sub>is</sub>		-	1.0	-	k Ω
Output Resistance	r <sub>oss</sub>		-	2.8	-	k Ω
Protective Diode Knee Voltage	V <sub>knee</sub>	I <sub>DIODE(REVERSE)</sub> = ±100 μA	-	±10	-	V

\*Limited only by practical design considerations.

†Capacitance between Gate No. 1 and all other terminals

‡Three-terminal measurement with Gate No. 2 and Source returned to guard terminal.

APPLICATIONS

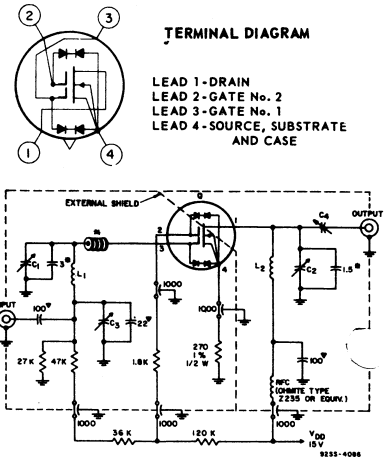
- RF amplifier, mixer, and IF amplifier in military, industrial, and consumer communications equipment
- aircraft and marine vehicular receivers
- CATV and MATV equipment
- telemetry and multiplex equipment

PERFORMANCE FEATURES

- superior cross-modulation performance and greater dynamic range than bipolar or single-gate FETs
- wide dynamic range permits large-signal handling before overload
- dual-gate permits simplified agc circuitry
- virtually no agc power required
- greatly reduces spurious responses in fm receivers
- permits use of vacuum-tube biasing techniques
- excellent thermal stability

DEVICE FEATURES

- back-to-back diodes protect each gate against handling and in-circuit transients
- low gate leakage currents —  
I<sub>G1SS</sub> & I<sub>G2SS</sub> = 20 nA(max.) at T<sub>A</sub> = 25°C
- high forward transconductance —  
g<sub>fs</sub> = 12,000 μmho (typ.)
- high unneutralized RF power gain —  
G<sub>PS</sub> = 18 dB (typ.) at 200 MHz
- low VHF noise figure — 3.5 dB (typ.) at 200 MHz



#Ferrite bead (4); Pyroferic Co., "Carbonyl J" 0.09 in. OD; 0.03 in. ID; 0.063 in. thickness.  
All resistors in ohms  
All capacitors in pF  
C<sub>1</sub>: 1.8 – 8.7 pF variable air capacitor: E.F. Johnson Type 160-104, or equivalent.  
C<sub>2</sub>: 1.5 – 5 pF variable air capacitor: E.F. Johnson Type 160-102, or equivalent.  
C<sub>3</sub>: 1 – 10 pF piston-type variable air capacitor: JFD Type VAM-010; Johnson Type 4335, or equivalent.  
C<sub>4</sub>: 0.8 – 4.5 pF piston type variable air capacitor: Erie 560-013 or equivalent.  
L<sub>1</sub>: 4 turns silver-plated 0.02-in. thick, 0.075-0.085-in. wide, copper ribbon. Internal diameter of winding = 0.25 in, winding length approx. 0.80 in.  
L<sub>2</sub>: 4½ turns silver-plated 0.02-in. thick, 0.085-0.095-in. wide, 5/16-in. ID. Coils = .90 in. long.

Fig. 1. 200-MHz Power gain and noise-figure test circuit

## Silicon Dual-Insulated-Gate Field-Effect Transistor

### N-Channel Depletion Type

### With Integrated Gate-Protection Circuits

**For RF Amplifier Applications up to 250 MHz**

RCA-40819 is an n-channel silicon, depletion type, dual insulated-gate field-effect transistor (FET).

The excellent overall performance characteristics of the RCA-40819 make it useful for a wide variety of rf-amplifier applications at frequencies up to 250 MHz. The two serially-connected channels with independent control gates make possible a greater dynamic range and lower cross-modulation than is normally achieved using devices having only a single control element.

The two-gate arrangement of the 40B19 also makes possible a desirable reduction in feedback capacitance by operating in the common-source configuration and ac grounding Gate No.2. The reduced capacitance allows operation at maximum gain *without neutralization* and reduces local oscillator feedthrough to the antenna – features of special importance in rf and if amplifiers.

Special back-to-back diodes are diffused directly into the MOS pellet and are electrically connected between each insulated gate and the FET's source. The diodes effectively bypass any voltage transients which exceed approximately  $\pm 10$  volts and protect the gates against damage in all normal handling and usage.

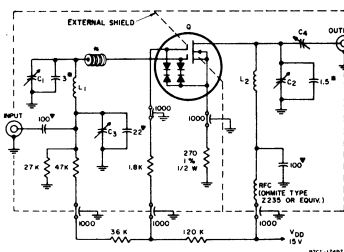
**ELECTRICAL CHARACTERISTICS**, at  $T_A = 25^\circ\text{C}$  unless otherwise specified

CHARACTERISTICS	SYMBOLS	TEST CONDITIONS	LIMITS			UNITS
			Min.	Typ.	Max.	
Gate-1-to-Source Cutoff Voltage	$V_{G1S(off)}$	$V_{DS} = +15\text{ V}$ , $I_D = 200\text{ }\mu\text{A}$ $V_{G2S} = +4\text{ V}$	—	—2	—4	V
Gate-No.2-to-Source Cutoff Voltage	$V_{G2S(off)}$	$V_{DS} = +15\text{ V}$ , $I_D = 200\text{ }\mu\text{A}$ $V_{G1S} = 0$	—	—2	—4	V
Gate-No.1-Leakage Current	$I_{G1SS}$	$V_{G1S} = \pm 6\text{ V}$ $V_{DS} = 0$ , $V_{G2S} = 0$	—	—	50	nA
Gate-No.2-Leakage Current	$I_{G2SS}$	$V_{G2S} = \pm 6\text{ V}$ $V_{DS} = 0$ , $V_{G1S} = 0$	—	—	50	nA
Zero-Bias Drain Current	$I_{DSS}$	$V_{DS} = +15\text{ V}$ $V_{G2S} = +4\text{ V}$ , $V_{G1S} = 0$	5	15	35	mA
Forward Transconductance (Gate-No.1-to-Drain)	$g_{fs}$	$V_{DS} = +15\text{ V}$ , $I_D = 10\text{ mA}$ $V_{G2S} = +4\text{ V}$ , $f = 1\text{ kHz}$	—	12,000	—	$\mu\text{mho}$
Small-Signal, Short-Circuit Input Capacitance†	$C_{iss}$	$V_{DS} = +15\text{ V}$ , $I_D = 10\text{ mA}$ $V_{G2S} = +4\text{ V}$ , $f = 1\text{ MHz}$	—	6	—	pF
Small-Signal, Short-Circuit, Reverse Transfer Capacitance (Drain-to-Gate No.1)†	$C_{rss}$		0.005	0.02	0.03	pF
Small-Signal, Short-Circuit Output Capacitance	$C_{oss}$		—	2	—	pF
Power Gain (see Fig. 1)	GPS	$V_{DS} = +15\text{ V}$ , $I_D = 10\text{ mA}$ $V_{G2S} = +4\text{ V}$ , $f = 200\text{ MHz}$	14	18	—	dB
Maximum Available Power Gain	MAG		—	20	—	dB
Maximum Usable Power Gain (unneutralized)	MUG		—	20*	—	dB
Noise Figure (see Fig. 1)	NF		—	3.5	6.0	dB
Magnitude of Forward Transadmittance	$ Y_{fS} $		—	12,000	—	$\mu\text{mho}$
Phase Angle of Forward Transadmittance	$\theta$		—	—35	—	degrees
Input Resistance	$r_{iss}$		—	1	—	k $\Omega$
Output Resistance	$r_{oss}$		—	2.8	—	k $\Omega$
Reverse Diode Knee Voltage	$V_{k, reverse}$	$I_{diode (reverse)} = \pm 100\text{ }\mu\text{A}$	—	$\pm 10$	—	V

\* Limited only by practical design considerations.

† Capacitance between Gate No.1 and all other terminals.

▲ Three-terminal measurement with Gate No 2 and Source returned to guard terminal.



*Fig. 1. 200 MHz power gain and noise figure test circuit*

For characteristics curves, refer to type 3N187.

The back-to-back diode configuration permits the 40819 to retain the wide input signal dynamic range inherent in the MOSFET. In addition, the low junction capacitance of these diodes adds little to the total capacitance shunting the signal gate.

The 25-volt drain-to-source rating permits the use of higher voltage power supplies.

The 40819 is hermtically sealed in the metal JEDEC TO-72 package.

### TERMINAL DIAGRAM

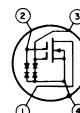
LEAD 1 - DRAIN

**LEAD 2 - GATE No.2**

**LEAD 3 - GATE No.1**

LEAD 4 - SOURCE,

### SUBSTRATE, AND CASE



### Device Features

- back-to-back diodes protect each gate against handling and in-circuit transients
- high forward transconductance:  $g_{fs} = 12,000 \mu\text{mho (typ.)}$
- high unneutralized RF power gain:  $G_{ps} = 18 \text{ dB (typ.) at } 200 \text{ MHz}$
- low VHF noise figure:  $3.5 \text{ dB (typ.) at } 200 \text{ MHz}$
- low gate leakage currents:  $I_{GSS} \text{ \& } I_{GSS2} = 50 \text{ nA at } T_A = 25^\circ \text{ C}$
- increased drain-to-source voltage:  $V_{DS} = -0.2 \text{ to } +25 \text{ V}$

### Performance Features

- superior cross-modulation performance and greater dynamic range than bipolar or single-gate FETs
- wide dynamic range permits large-signal handling before overload
- virtually no agc power required
- greatly reduces spurious responses in FM receivers
- dual gate permits simplified AGC circuitry

## Applications

- RF amplifier, mixer, and IF amplifier in military, industrial, and consumer communications equipment
- aircraft and marine vehicular receivers
- CATV and MATV equipment
- telemetry and multiplex equipment

**Absolute Maximum Values, at  $T_A = 25^\circ\text{C}$**

Drain-to-Source Voltage, $V_{DS}$ .....	-0.2 to +25	V
Gate Terminal Current, $I_{G1}$ or $I_{G2}$ .....	$\pm 100$	$\mu A$
Drain-to-Gate Voltage, $V_{DG1}$ or $V_{DG2}$ .....	+31	V
Drain Current, $I_D$ .....	50	mA
Transistor Dissipation, $P_T$ :		
At $T_A$ up to 25°C .....	330	mW
At $T_A$ above 25°C .....	derate linearly 2.2 mW/°C	
Ambient Temperature Range:		
Operating and Storage .....	-65 to +175	°C
Lead Temperature (During Soldering):		
At distances 1/32 in from seating surface for 10 s max. ....	265	°C

### Maximum Ratings

**Continuous Working Voltage<sup>#</sup>, at  $T_A = 25^\circ\text{C}$ :**

Gate No.1-to-Source Voltage, $V_{G1S}$ ..	-6 to +3	V
Gate No.2-to-Source Voltage, $V_{G2S}$ ..	-6 to +6 or 40% of $V_{DS}$ (whichever value is less)	V
Drain-to-Gate Voltage, $V_{DG1}$ or $V_{DG2}$ .....	+25	V

Continuous Working Voltage Ratings must be observed to maintain device characteristics. These ratings are based on long-term continuous voltage operation but may be exceeded for short durations (e.g. testing of device characteristics), provided the absolute Maximum Ratings are not exceeded.



ELECTRICAL CHARACTERISTICS at  $T_A = 25^\circ\text{C}$ 

CHARACTERISTICS	SYMBOLS	TEST CONDITIONS	LIMITS						UNITS		
			40820			40821					
			Min.	Typ.	Max.	Min.	Typ.	Max.			
Gate No. 1 to Source Cutoff Voltage	V <sub>G1S(off)</sub>	V <sub>DS</sub> = +18V, I <sub>D</sub> = 200μA, V <sub>G2S</sub> = +4V	-	-1	-3	-	-1	-3	V		
Gate No. 2 to Source Cutoff Voltage	V <sub>G2S(off)</sub>	V <sub>DS</sub> = +18V, I <sub>D</sub> = 200μA, V <sub>G1S</sub> = 0	-	-1	-3	-	-1	-3	V		
Gate to Source Forward Breakdown Voltage: Gate No. 1	V <sub>(BR)G1SSF</sub>	I <sub>G1SSF</sub> I <sub>G2SSF</sub> 100 μA	V <sub>G2S</sub>	V <sub>DS</sub>	0	-	9	-	11	-	V
	Gate No. 2	V <sub>(BR)G2SSF</sub>	V <sub>G1S</sub>	V <sub>DS</sub>	0	-	9	-	11	-	V
Gate to Source Reverse Breakdown Voltage: Gate No. 1	V <sub>(BR)G1SSR</sub>	I <sub>G1SSR</sub> I <sub>G2SSR</sub> 100 μA	V <sub>G2S</sub>	V <sub>DS</sub>	0	-	9	-	11	-	V
	Gate No. 2	V <sub>(BR)G2SSR</sub>	V <sub>G1S</sub>	V <sub>DS</sub>	0	-	9	-	11	-	V
Gate No. 1 Terminal Forward Current	I <sub>G1SSF</sub>	V <sub>DS</sub> V <sub>G2S</sub> 0	V <sub>G1S</sub> 6 V	-	-	50	-	-	-	nA	
			V <sub>G1S</sub> 4.5 V	-	-	-	-	-	50	nA	
Gate No. 1 Terminal Reverse Current	I <sub>G1SSR</sub>	V <sub>DS</sub> V <sub>G2S</sub> 0	V <sub>G1S</sub> 6 V	-	-	50	-	-	-	nA	
			V <sub>G1S</sub> 4.5 V	-	-	-	-	50	-	nA	
Gate No. 2 Terminal Forward Current	I <sub>G2SSF</sub>	V <sub>DS</sub> V <sub>G1S</sub> 0	V <sub>G2S</sub> 6 V	-	-	50	-	-	-	nA	
			V <sub>G2S</sub> 4.5 V	-	-	-	-	50	-	nA	
Gate No. 2 Terminal Reverse Current	I <sub>G2SSR</sub>	V <sub>DS</sub> V <sub>G1S</sub> 0	V <sub>G2S</sub> -6 V	-	-	50	-	-	-	nA	
			V <sub>G2S</sub> 4.5 V	-	-	-	-	50	-	nA	
Zero Bias Drain Current	I <sub>DS</sub>	V <sub>DS</sub> -15 V, V <sub>G1S</sub> 0, V <sub>G2S</sub> -4 V	0.5	8	15	0.5	8	20	nA		
Forward Transconductance (Gate No. 1-to-Drain)	g <sub>fs</sub>	V <sub>DS</sub> -15 V I <sub>D</sub> 10 mA V <sub>G2S</sub> -4 V	f 1 kHz	-	12000	-	12000	-	μmho		
Small Signal, Short Circuit Input Capacitance <sup>Ⓢ</sup>	C <sub>iss</sub>			6	8.5	-	6	9	pF		
Small Signal, Short Circuit, Reverse Transfer Capacitance (Drain to Gate No. 1) <sup>Ⓢ</sup>	C <sub>rss</sub>		f 1 MHz	0.005	0.02	0.03	0.005	0.02	0.04	pF	
Small Signal, Short Circuit Output Capacitance	C <sub>oss</sub>			2	-	-	2	-	pF		
Power Gain (see Fig. 6)	G <sub>PS</sub>			14	17	-	-	-	dB		
Noise Figure (see Fig. 6)	NF	G <sub>PS(C)</sub>	f 200 MHz	-	4.5	6	-	-	dB		
Conversion Gain			f 200/44 MHz	-	-	-	11	-	dB		

<sup>Ⓢ</sup> Capacitance between Gate No. 1 and all other terminals.

<sup>Ⓢ</sup> Three terminal measurement with Gate No. 2 and Source returned to guard terminal.

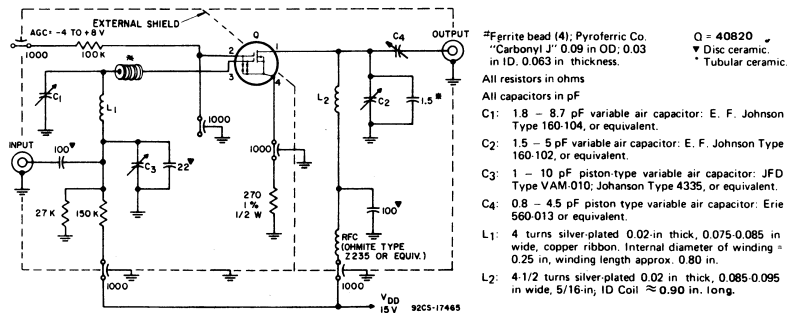


Fig. 2 - 200 MHz power gain and noise figure test circuit for type 40820.

Table 1 -  $y$  parameters vs. frequency

CHARACTERISTICS	SYMBOL	FREQUENCY (MHz)				UNITS
		50	100	200	250	
Y Parameters						
Input Conductance	$g_{is}$	0.08	0.33	1.0	1.6	mmho
Input Susceptance	$b_{is}$	1.8	3.6	7.5	9.8	mmho
Magnitude Forward Transadmittance	$ y_{fs} $	12	12	12	12.3	mmho
Angle of Forward Transadmittance	$\angle y_{fs}$	-2	-13	-35	-45	degree
Output Conductance	$g_{os}$	0.10	0.18	0.36	0.42	mmho
Output Susceptance	$b_{os}$	0.5	1.0	2.0	2.6	mmho
Magnitude of Reverse Transadmittance	$ y_{rs} $	8	12	25	40	$\mu$ mho
Angle of Reverse Transadmittance	$\angle y_{rs}$	-88	-73	-25	-10	degree

40822-40823

Silicon Dual-Insulated-Gate Field-Effect Transistors

N-Channel Depletion Types

With Integrated Gate-Protection Circuits

For FM Tuner Applications

40822 - RF Amplifier 40823 - Mixer

RCA 40822 and 40823 are n-channel silicon, depletion type, dual-insulated-gate, field-effect transistors for RF amplifier (40822) and mixer (40823) applications in FM receivers and other commercial equipment operating at frequencies up to 150 MHz.

These devices designed for VHF performance, provide excellent power gain, low-noise figures and have wide dynamic range. The dual-gate feature offers good cross-modulation performance over the AGC range and reduces feedback capacitance by shielding Gate No. 1 from the drain. The very low feedback capacitance also eliminates the need for circuit neutralization and reduces local oscillator feed-through to the antenna.

Virtually no power is required in AGC utilizing the 40822 and 40823. In addition, these devices minimize input impedance variations and automatically achieve AGC delay when AGC is applied to Gate No. 2. The dual-gate

Performance Features

- superior cross-modulation performance and greater dynamic range than bipolar or single-gate FET's
- wide dynamic range permits large-signal handling before overload
- virtually no agc power required
- greatly reduces spurious responses in FM receivers
- dual gate permits simplified AGC circuitry

arrangement also makes it possible to isolate the local oscillator signal from the incoming signal by applying each signal to a specific gate.

Back-to-back diodes, diffused directly into the MOS pellet, protect the gates against damage in normal handling and usage by limiting transient voltages that exceed +10 volts. The 40822 and 40823 are hermetically sealed in metal JEDEC TO-72 packages.

Device Features

- back-to-back diodes protect each gate against handling and in-circuit transients
- high forward transconductance:  $g_{fs} = 12,000 \mu\text{mho}$  (typ.)
- high unneutralized RF power gain:  $G_{PS} = 24 \text{ dB}$  (typ.) at 100 MHz (40822)
- low VHF noise figure: 2 dB (typ.) at 100 MHz (40822)
- low gate leakage currents:  $I_{G1SS} \& I_{G2SS} = 50 \text{ nA}$  at  $T_A = 25^\circ\text{C}$

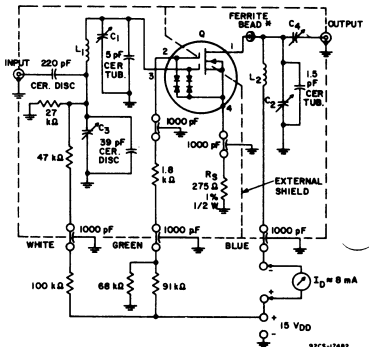


Fig. 1 - 100/10.7-MHz conversion power gain test circuit for type 40823.

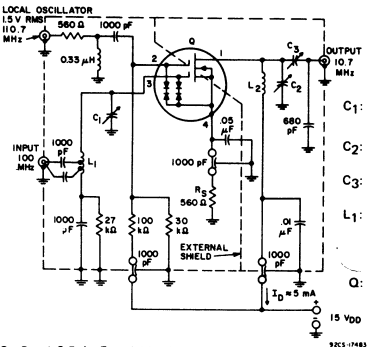
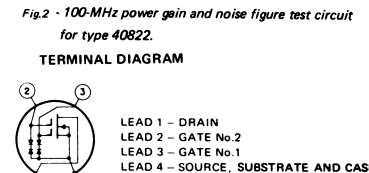


Fig. 2 - 100-MHz power gain and noise figure test circuit for type 40822.



Maximum Ratings		40822	40823
Continuous Working Voltage <sup>#</sup> , at $T_A = 25^\circ\text{C}$ :			
Gate No. 1-to-Source Voltage, $V_{G1S}$		-6 to +3	-4.5 to +3
Gate No. 2-to-Source Voltage, $V_{G2S}$		-6 to +6 or 40% of $V_{DS}$ (whichever value is less)	-4.5 to +4.5 or 40% of $V_{DS}$ (whichever value is less)
Drain-to-Gate Voltage, $V_{DG1}$ or $V_{DG2}$		+20	+20
Absolute Maximum Values, at $T_A = 25^\circ\text{C}$ :			
Drain-to-Source Voltage, $V_{DS}$		-0.2 to +18	-0.2 to +18
Gate Terminal Current, $I_{G1S}$ or $I_{G2S}$		$\pm 100$	$\pm 100$
Drain-to-Gate Voltage, $V_{DG1}$ or $V_{DG2}$		+24	+22.5
Drain Current, $I_D$		50	50
Transistor Dissipation:			
At $T_A$ up to $25^\circ\text{C}$		330	330
At $T_A$ above $25^\circ\text{C}$		derate linearly 2.2 mW/ $^\circ\text{C}$	
Ambient Temperature Range:			
Operating and Storage		-65 to +175	-65 to +175
Lead Temperature (During Soldering):			
At distances 1/32 in from seating surface for 10 s max.		265	265

<sup>#</sup> Continuous Working Voltage Ratings must be observed to maintain device characteristics. These ratings are based on long-term continuous voltage operation but may be exceeded for short durations (e.g. testing of device characteristics), provided the Absolute Maximum Ratings are not exceeded.

CHARACTERISTICS	SYMBOLS	TEST CONDITIONS	LIMITS						UNITS	
			40822			40823				
			Min	Typ.	Max.	Min.	Typ.	Max.		
Gate No. 1-to-Source Cutoff Voltage	$V_{G1S(off)}$	$V_{DS}=+15\text{V}, I_D=200\mu\text{A}, V_{G2S}=+4\text{V}$	—	—	-2	-4	—	-2	-4	V
Gate No. 2-to-Source Cutoff Voltage	$V_{G2S(off)}$	$V_{DS}=+15\text{V}, I_D=200\mu\text{A}, V_{G1S}=0$	—	—	-2	-4	—	-2	-4	V
Gate-to-Source Forward Breakdown Voltage: Gate No. 1	$V_{(BR)G1SSF}$	$I_{G1SSF} = I_{G2SSF} = 100\mu\text{A}$ $V_{G2S} = V_{DS} = 0$ $V_{G1S} = V_{DS} = 0$	—	9	—	—	11	—	—	V
	Gate No. 2		$V_{(BR)G2SSF}$	—	9	—	—	11	—	V
Gate-to-Source Reverse Breakdown Voltage: Gate No. 1	$V_{(BR)G1SSR}$	$I_{G1SSR} = I_{G2SSR} = 100\mu\text{A}$ $V_{G2S} = V_{DS} = 0$ $V_{G1S} = V_{DS} = 0$	—	9	—	—	11	—	—	V
	Gate No. 2		$V_{(BR)G2SSR}$	—	9	—	—	11	—	V
Gate No. 1-Terminal Forward Current	$I_{G1SSF}$	$V_{DS} = V_{G2S} = 0$ $V_{G1S} = 6\text{V}$ $V_{G1S} = 4.5\text{V}$	—	—	—	50	—	—	—	nA
			$V_{G1S} = 4.5\text{V}$	—	—	—	—	50	—	nA
Gate No. 1-Terminal Reverse Current	$I_{G1SSR}$	$V_{DS} = V_{G2S} = 0$ $V_{G1S} = -6\text{V}$ $V_{G1S} = -4.5\text{V}$	—	—	—	50	—	—	—	nA
			$V_{G1S} = -4.5\text{V}$	—	—	—	—	50	—	nA
Gate No. 2-Terminal Forward Current	$I_{G2SSF}$	$V_{DS} = V_{G1S} = 0$ $V_{G2S} = 6\text{V}$ $V_{G2S} = 4.5\text{V}$	—	—	—	50	—	—	—	nA
			$V_{G2S} = 4.5\text{V}$	—	—	—	—	50	—	nA
Gate No. 2-Terminal Reverse Current	$I_{G2SSR}$	$V_{DS} = V_{G1S} = 0$ $V_{G2S} = -6\text{V}$ $V_{G2S} = -4.5\text{V}$	—	—	—	50	—	—	—	nA
			$V_{G2S} = -4.5\text{V}$	—	—	—	—	50	—	nA
Zero-Bias Drain Current	$I_{DS}$	$V_{DS} = +15\text{V}, V_{G1S} = 0, V_{G2S} = +4\text{V}$	5	15	30	5	15	35	mA	
Forward Transconductance (Gate No. 1-to-Drain)	$g_{fs}$	$V_{DS} = +15\text{V}$ $I_D = 10\text{mA}$ $V_{G2S} = +4\text{V}$	$f = 1\text{kHz}$	—	12000	—	—	12000	—	$\mu\text{mho}$
Small Signal, Short-Circuit Input Capacitance <sup>1</sup>	$C_{iss}$		$f = 1\text{MHz}$	—	6.5	9.5	—	6.5	10	pF
Small Signal, Short-Circuit, Reverse Transfer Capacitance (Drain-to-Gate-No. 1) <sup>1</sup>	$C_{rss}$			0.005	0.020	0.030	0.005	0.025	0.045	pF
Small Signal, Short-Circuit Output Capacitance	$C_{oss}$			—	2	—	—	2	—	pF
Power Gain (see Fig. 5)	$G_{PS}$		$f = 100\text{MHz}$	19	24	—	—	—	—	dB
Noise Figure (see Fig. 5)	NF	$f = 100\text{MHz}$	—	2	3.5	—	—	—	dB	
Conversion Gain	$G_{p(C)}$	$f = 100\text{ to } 10.7\text{MHz}$	—	—	—	14	18	—	dB	

<sup>1</sup> Capacitance between Gate No. 1 and all other terminals. <sup>2</sup> Three-terminal measurement with Gate No. 2 and Source returned to guard terminal.

For characteristics curves, refer to type 3N187.



# Silicon Dual-Insulated Gate Field-Effect Transistor

## N-Channel Depletion Type

### With Integrated Gate-Protection Circuits

### General-Purpose Economy Type for Applications from DC to 500 MHz

RCA-40841 is an n-channel silicon, depletion type, dual-insulated gate, field-effect transistor intended for general-purpose applications from DC to frequencies up to 500 MHz.

This MOS/FET provides excellent power gain, linear-circuit operation and has a wide dynamic operating range. Its square-law characteristics result in low cross-modulation performance over the AGC range. Its dual-gate construction reduces feedback capacitance by shielding Gate No. 1 from the drain, and makes it possible to isolate the local oscillator signal from the incoming signal by applying the two signals to separate gates. The very low feedback capacitance of this device eliminates the need for neutralization in circuits using the dual-gate configuration. Use of the device in the RF input stage of a receiver reduces local oscillator feed-through to the antenna. The 40841 requires negligible AGC power, provides automatic delay when AGC is applied to Gate No. 1 and exhibits slight input impedance variations during AGC functioning. The device has exceptionally high input impedance, an attribute for timing-circuit design.

Back-to-back diodes are fabricated on the same monolithic silicon pellet as the MOS/FET to protect the gates against damage due to electrostatic charges frequently encountered during normal handling. These back-to-back diodes also function as "transient trappers" by limiting in-circuit transient voltages that exceed  $\pm 10$  volts.

Maximum ratings and electrical characteristics are included in the data for operation of the 40841 as the equivalent of a single-gate device. For single-gate operation, connect Gate No. 1 (Term. 2) to Gate No. 2 (Term. 3), as shown in the Terminal Diagrams on Page 2. The 40841 MOS/FET is hermetically sealed in the metal JEDEC TO-72 package.

### Device Features:

- back-to-back diodes protect gate insulation against damage due to static charges frequently encountered during handling
- high forward transconductance:  $g_{fs} = 12,000 \mu\text{mho}$  (typ.)
- high power gain:  $G_{ps} = 32 \text{ dB}$  (typ.) at 44 MHz
- gate leakage currents:  $I_{G1SS}$  and  $I_{G2SS} = 60 \text{ nA}$  (max.) at  $T_A = 25^\circ\text{C}$
- high input impedance
- excellent thermal stability

### Performance Features:

- superior cross-modulation performance and greater dynamic range than bipolar and junction-gate FETs
- wide dynamic range permits large-signal handling before overloading
- virtually no agc power required
- greatly reduced spurious responses in AM and FM receivers
- dual-gate configuration permits simplified AGC circuitry
- operates at frequencies to 500 MHz without neutralization in circuits utilizing the dual-gate configuration
- operates up to UHF with low-noise performance

The following dual-gate MOS/FET types are specified for applications requiring premium-grade performance: 3N200, 3N187, 40673, 40819, 40820, 40821, 40822, and 40823.

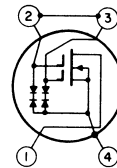
Detailed information, utilizing RCA dual-gate protected MOS/FETs in RF applications, is given in the following RCA Application Notes: AN-4431 "RF Applications of the Dual-Gate MOS/FET up to 500 MHz" and AN-4018 "Design of Gate-Protected MOS Field-Effect Transistors".

### Applications:

- DC amplifiers
- RF amplifiers
- mixers
- IF amplifiers
- video amplifiers
- differential amplifiers
- frequency multipliers
- phase splitters
- industrial timers — long time delays
- thyristor trigger circuits
- choppers
- voltage-controlled attenuators
- constant-current source
- voltage regulators
- telemetry & multiplex
- servo amplifiers
- proximity switches

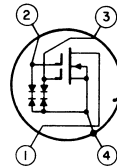
### TERMINAL DIAGRAMS

#### SINGLE-GATE CONFIGURATION



LEAD 1—DRAIN  
LEADS 2 AND 3—GATE  
LEAD 4—SOURCE,  
SUBSTRATE AND CASE

#### DUAL-GATE CONFIGURATION



LEAD 1—DRAIN  
LEAD 2—GATE No. 2  
LEAD 3—GATE No. 1  
LEAD 4—SOURCE  
SUBSTRATE AND CASE

### Maximum Ratings

#### Absolute Maximum Values, at $T_A = 25^\circ\text{C}$ :

Drain-to-Source Voltage, $V_{DS}$	—0.2 to +18
Gate Terminal Current, $I_{G1S}$ or $I_{G2S}$	$\pm 100$
Gate Terminal Current, $I_{GS}$	$\pm 100$
Drain-to-Gate Voltage, $V_{DG1}$ or $V_{DG2}$	+24
Drain-to-Gate Voltage, $V_{DG}$	—50
Drain Current, $I_D$	50
Transistor Dissipation:	
At $T_A$ up to $25^\circ\text{C}$	330
At $T_A$ above $25^\circ\text{C}$	derate linearly 2.2 mW/ $^\circ\text{C}$

#### Ambient Temperature Range:

Operating and Storage	—65 to +175
Lead Temperature (During Soldering):	
At distances 1/32 in from seating surface for 10 s max.	265

#### Continuous Working Voltage<sup>#</sup>, at $T_A = 25^\circ\text{C}$ :

Gate No. 1-to-Source Voltage, $V_{G1S}$	—4.5 to +3
Gate No. 2-to-Source Voltage, $V_{G2S}$	—4.5 to +4.5 or 40% of $V_{DS}$ (whichever value is less)

Gate-to-Source Voltage, $V_{GS}$	—
Drain-to-Gate Voltage, $V_{DG1}$ or $V_{DG2}$	+20
Drain-to-Gate Voltage, $V_{DG}$	—

<sup>#</sup>Continuous Working Voltage Ratings must be observed to maintain device characteristics. These ratings are based on long-term continuous voltage operation but may be exceeded for short durations (e.g. testing of device characteristics), provided the Absolute Maximum Ratings are not exceeded.

Dual-Gate Configuration	Single-Gate Configuration	
—0.2 to +18	—0.2 to +18	V
$\pm 100$	—	$\mu\text{A}$
$\pm 100$	$\pm 100$	$\mu\text{A}$
+24	—	V
—50	+24	V
50	50	mA
330	330	mW
derate linearly 2.2 mW/ $^\circ\text{C}$		
—65 to +175	—65 to +175	$^\circ\text{C}$
265	265	$^\circ\text{C}$
—4.5 to +3	—	V
—4.5 to +4.5 or 40% of $V_{DS}$ (whichever value is less)	—	V
+20	—	V
—	+20	V

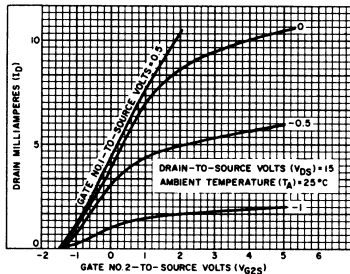


Fig. 2— $I_D$  vs.  $V_{G2S}$ .

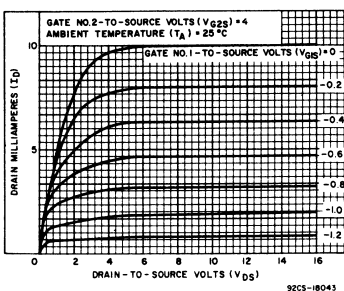


Fig. 3— $I_D$  vs.  $V_{DS}$ .

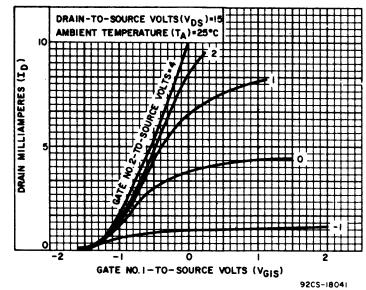


Fig. 1— $I_D$  vs.  $V_{G1S}$ .

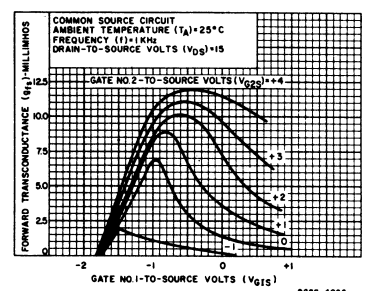


Fig. 4— $g_{fs}$  vs.  $V_{G1S}$ .

40841

ELECTRICAL CHARACTERISTICS at  $T_A = 25^\circ\text{C}$

CHARACTERISTICS	SYMBOLS	TEST CONDITIONS	LIMITS						UNITS	
			CONFIGURATION			SINGLE-GATE				
			DUAL.	TYP.	MAX.	MIN.	TYP.	MAX.		
Gate-to-Source Cutoff Voltage:										
Dual-Gate (No. 1)	$V_{G1S}(\text{off})$	$V_{DS} = +15\text{V}, I_D = 200\mu\text{A}, V_{G2S} = +4\text{V}$	-	-2	-	-	-	-	V	
Dual-Gate (No. 2)	$V_{G2S}(\text{off})$	$V_{DS} = +15\text{V}, I_D = 200\mu\text{A}, V_{G1S} = 0$	-	-2	-	-	-	-	V	
Single Gate	$V_{GS}(\text{off})$	$V_{DS} = +15\text{V}, I_D = 200\mu\text{A}$	-	-	-	-	-1.6	-	V	
Gate-to-Source Forward Breakdown Voltage:										
Dual-Gate (No. 1)	$V(\text{BR}G1\text{SSF})$	$I_{G1\text{SSF}} = 100\mu\text{A}, V_{G2S} = V_{DS} = 0$	-	9	-	-	-	-	V	
Dual-Gate (No. 2)	$V(\text{BR}G2\text{SSF})$	$I_{G2\text{SSF}} = 100\mu\text{A}, V_{G1S} = V_{DS} = 0$	-	9	-	-	-	-	V	
Single Gate	$V(\text{BR}G\text{SSF})$	$I_{G\text{SSF}} = 100\mu\text{A}, V_{DS} = 0$	-	-	-	-	9	-	V	
Gate-to-Source Reverse Breakdown Voltage:										
Dual-Gate (No. 1)	$V(\text{BR}G1\text{SSR})$	$I_{G1\text{SSR}} = 100\mu\text{A}, V_{G2S} = V_{DS} = 0$	-	9	-	-	-	-	V	
Dual-Gate (No. 2)	$V(\text{BR}G2\text{SSR})$	$I_{G2\text{SSR}} = 100\mu\text{A}, V_{G1S} = V_{DS} = 0$	-	9	-	-	-	-	V	
Single Gate	$V(\text{BR}G\text{SSR})$	$I_{G\text{SSR}} = 100\mu\text{A}, V_{DS} = 0$	-	-	-	-	9	-	V	
Gate Terminal Forward Current:										
Dual-Gate (No. 1)	$I_{G1\text{SSF}}$	$V_{DS} = V_{G2S} = 0, V_{G1S} = 6\text{V}$	-	-	60	-	-	-	nA	
Dual Gate (No. 2)	$I_{G2\text{SSF}}$	$V_{DS} = V_{G1S} = 0, V_{G2S} = 6\text{V}$	-	-	60	-	-	-	nA	
Single-Gate	$I_{G\text{SSF}}$	$V_{DS} = 0, V_{GS} = 6\text{V}$	-	-	-	-	-	120	nA	
Gate Terminal Reverse Current:										
Dual-Gate (No. 1)	$I_{G1\text{SSR}}$	$V_{DS} = V_{G2S} = 0, V_{G1S} = -6\text{V}$	-	-	60	-	-	-	nA	
Dual-Gate (No. 2)	$I_{G2\text{SSR}}$	$V_{DS} = V_{G1S} = 0, V_{G2S} = -6\text{V}$	-	-	60	-	-	-	nA	
Single-Gate	$I_{G\text{SSR}}$	$V_{DS} = 0, V_{GS} = -6\text{V}$	-	-	-	-	-	120	nA	
Zero-Bias Drain Current:										
Dual-Gate	$I_{DS}$	$V_{DS} = +15\text{V}, V_{G1S} = 0, V_{G2S} = +4\text{V}$	-	10	-	-	-	-	mA	
Single-Gate	$I_{DSS}$	$V_{DS} = +15\text{V}, V_{GS} = 0$	-	-	-	-	3.7	-	mA	
Forward Transconductance (Gate-to-Drain)										
Dual-Gate	$g_{fs}$	$V_{DS} = +15\text{V}$ $I_D = 10\text{mA}$ <div>Dual-Gate only <math>V_{G2S} = +4\text{V}</math></div>	1 kHz	-	12000	-	-	-	$\mu\text{mho}$	
Single-Gate	$g_{fs}$			-	-	-	-	7000	-	$\mu\text{mho}$
Small-Signal, Short-Circuit Input Capacitance†										
Dual-Gate	$C_{iss}$	$V_{DS} = +15\text{V}$ $I_D = 10\text{mA}$ <div>Dual-Gate only <math>V_{G2S} = +4\text{V}</math></div>	f = 1 MHz	-	6.5	-	11	-	pF	
Small-Signal, Short-Circuit, Reverse Transfer Capacitance (Drain-to-Gate No. 1)†										
Dual-Gate	$C_{rss}$			-	0.02	-	0.54	-	pF	
Small-Signal, Short-Circuit Output Capacitance										
Dual-Gate	$C_{oss}$	$V_{DS} = +15\text{V}$ $I_D = 10\text{mA}$ <div>Dual-Gate only <math>V_{G2S} = +4\text{V}</math></div>	f = 1 kHz	-	2	-	2	-	pF	
Audio Spot Noise Figure*										
Dual-Gate	NF			-	0.46	-	-	-	dB	
Single-Gate	NF	$V_{DS} = +15\text{V}$ $I_D = 10\text{mA}$ <div>Dual-Gate only <math>V_{G2S} = +4\text{V}</math></div>	f = 1 kHz	-	-	-	0.29	-	dB	
Power Gain										
Dual-Gate	$G_{ps}$			44 MHz	-	32	-	-	-	dB
Conversion Gain										
Dual-Gate	$G_{ps(C)}$	$V_{DS} = +15\text{V}$ $I_D = 10\text{mA}$ <div>Dual-Gate only <math>V_{G2S} = +4\text{V}</math></div>	44 MHz	-	24	-	-	-	dB	

1 Capacitance between Gate No. 1 and all other terminals (Dual-Gate), Gate and all other terminals (Single-Gate)

\* Three-terminal measurement with Gate No. 2 and Source returned to guard terminal (Dual-Gate)

\* Noise Figure =  $10 \log_{10} \left[ 1 + \frac{e_n^2}{4KT BW R_g} \right]$  where  $K = 1.38 \times 10^{-23}$ ,  $T$  = Temperature in  $^\circ\text{Kelvin}$ ;  $BW$  = Bandwidth in Hz;  $R_g$  = Generator resistance

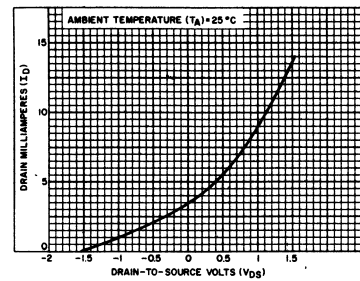


Fig. 7— $I_D$  vs.  $V_{DS}$ .

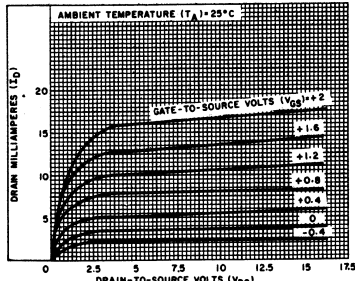


Fig. 8— $I_D$  vs.  $V_{GS}$ .

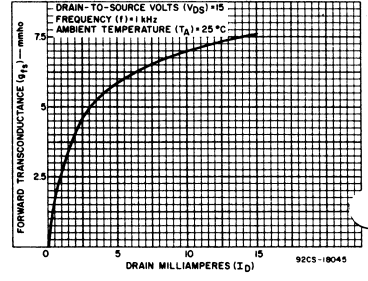


Fig. 9— $g_{fs}$  vs.  $I_D$ .

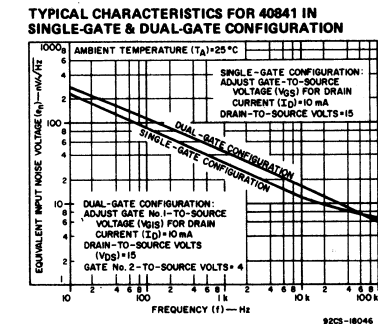


Fig. 10— $e_n$  vs.  $f$ .

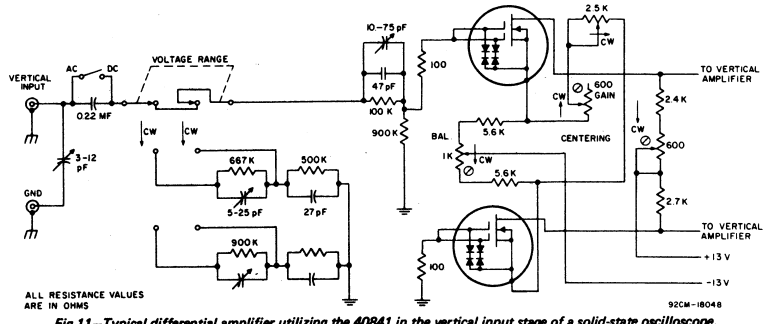
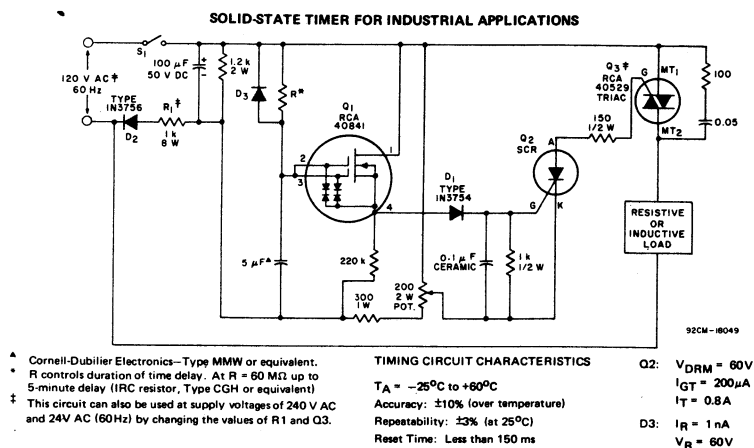


Fig. 11—Typical differential amplifier utilizing the 40841 in the vertical input stage of a solid-state oscilloscope.



**Fig.12—Typical timing circuit utilizing the 40841 in a single-gate configuration.**